
Poster Presentation

[OLEDp1]OLED poster

Thu. Nov 28, 2019 10:40 AM - 1:10 PM Main Hall (1F)

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[OLEDp1-7]A Study of Encapsulation Structure for TFT Reliability in Top Emission OLED Display

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Preventing hydrogen and water vapor from permeating through encapsulation layer plays an important role in TFT Reliability. To improve a blocking characteristic, encapsulation inorganic layers were studied. A SiN_x and SiO₂ multilayered inorganic deposition method for OLED has been developed to obtain a reliable performance.